



PXD6 long matrix status and testing preparations

13th International Workshop on DEPFET Detectors and Applications

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Outline

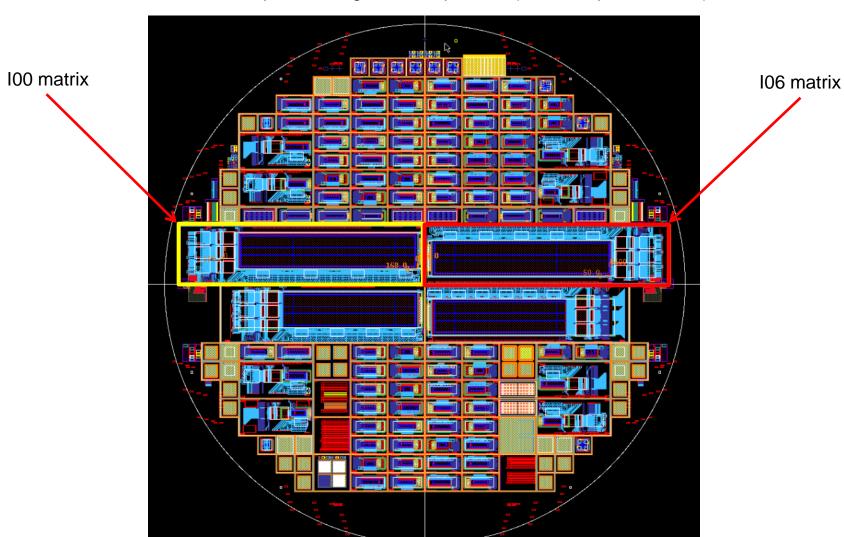


- PXD6 status: batch II & III
- PXD6 large matrices layout
- Testing plans
- Test Systems, in particular Hybrid 6.0
- Summary and Outlook

PXD6 batch III



2 SOI wafers with DHP0.2 footprint waiting for Cu deposition (will be deposited soon).



PXD6 batch II & III



Differences between batch II and batch III

Batch II:

4 wafers (3 SOI + 1 ref)

no DHP footprint

shorts in the large PXD6 matrices

none working large PXD6

Batch III:

2 wafers (SOI) à 4 large PXD6

DHP footprint

changed Aluminium 2 layer in order to deposit copper

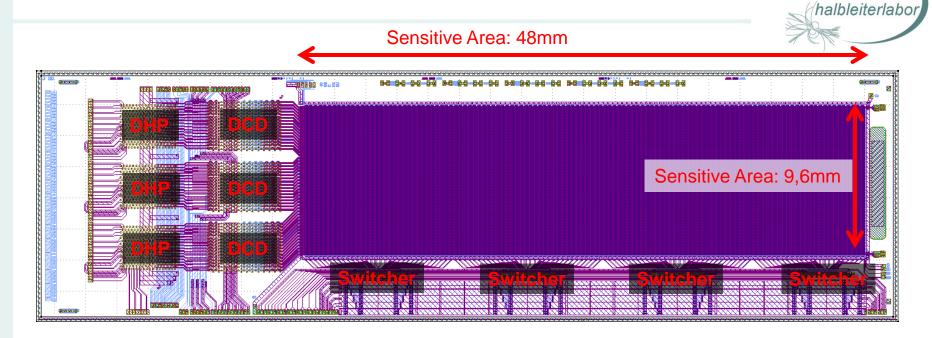
Copper pads are included (in order to solder the ASICs)

Current status:

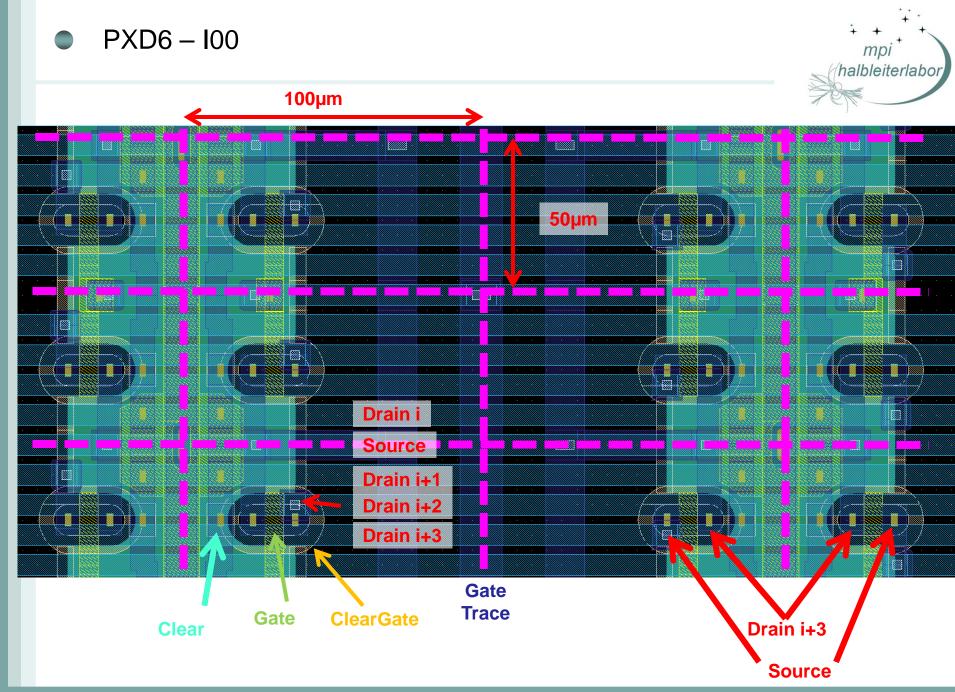
2 PXD6 matrices are tested and work properly

Copper layer is still missing => will be done soon

PXD6 – I00



- Capacitive coupled clear-gate (provides Clear mechanism but harms Gated-Mode Operation)
- Enhanced drift field
- 50 x 100 μm² pixel size
- 192 x 480 pixels
 - 768 drain lines → 3 DCDs & 3 DHPs
 - 120 gate/clear lines → 4 SWITCHERs



PXD6 – 106



Sensitive Area: 48mm



- Standard Belle II design
- 50 x 75 μm² pixel size
- 192 x 640 pixels
 - 768 drain lines → 3 DCDs & 3 DHPs
 - 160 gate/clear lines → 5 SWITCHERs

Both matrices have the same sensitive area

PXD6 - 106 mpi halbleiterlabor **75μm** 50µm



PXD6 Status Verification Tests

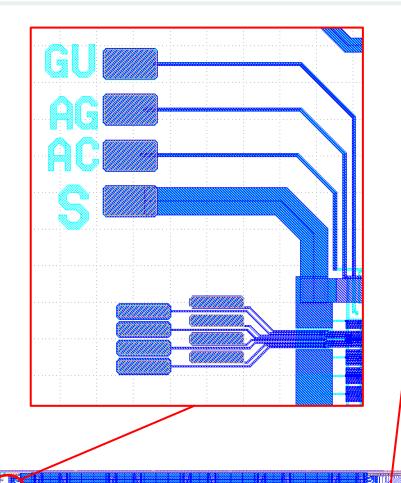
PXD6 long matrices testing plans

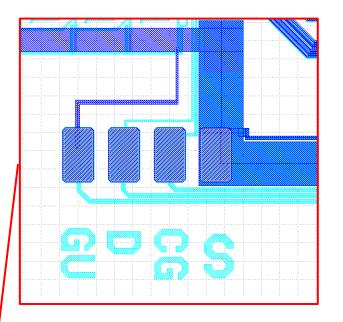


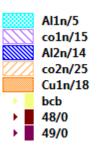
- 1. Verify the status of the matrices on the wafers (pretested after Al2)
- 2. Measure the output characteristics for all the (768) DEPFETs on one electrical row
- 3. Check for shorts/opens in the two metal layers in the peripheral region to be performed at ATG, as in the case of the EMCM
- Instrumentation for tests no. 1, and 2.:
 - Probe station PA200 equipped with two flying needles and four static needles
 - ➤ Keithley 4200 SCS measurement system
- Instrumentation for test no. 3.:
 - ➤ ATG Flying probe system (S2 machine ref. to C. Koffmane's talk)

Verification of the PXD6-batch III matrices' status [I]



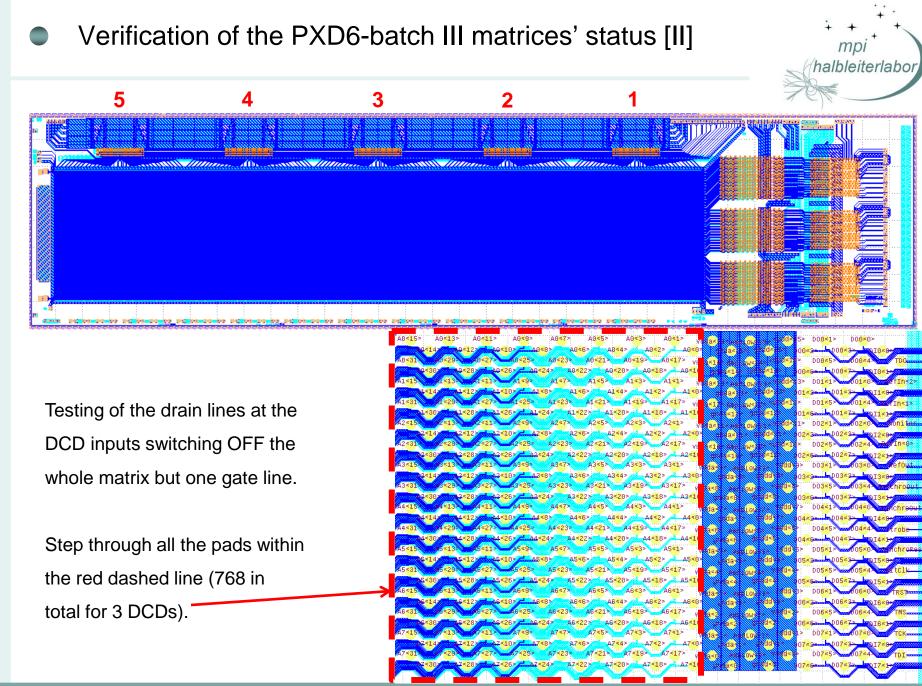






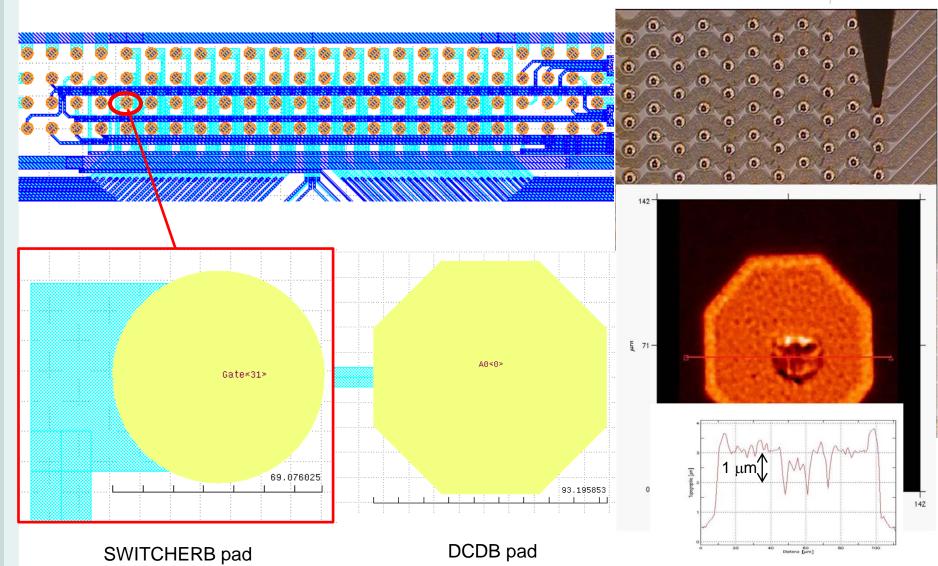
Verify the status of the matrices on the wafers measuring the characteristics of:

- All Gates vs All Clear (bulk)
- All Gates vs Clear Gate
- All Clears vs Source
 - All Clears vs Clear Gate



Challenges of the testing







Test Systems

- EMCM
- Hybrid 5
- Hybrid 6

EMCM, Hybrid 5, Hybrid 6



	EMCM	Hybrid 5	Hybrid 6
Matrix	Small	Small	Large
DCD	1 (4) (128 of 256 channels)	1 (128 of 256 channels)	3
DHP	1 (4) (128 of 256 channels)	1 (128 of 256 channels)	3
Switcher	1 (6) (16 of 32 channels)	1 (16 of 32 channels)	4 OR 5
Connector	Kapton DataPatchPanel (DPP) – 2Infiniband PowerPatchPanel(PPP) – MircoDSub	2 Infiniband (data) Samtec IPD1 (Power)	4 Infiniband (data) MicroDSub (Power)
DHH	•	✓	•
DHH Emulator	•	•	NO (3 DCDs, DHPs)



Almost same setup: 128 drains, 1 Switcher, small PXD6

Difference: Kapton

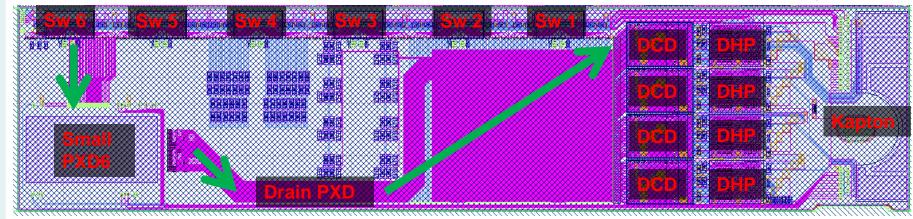
Same power cable as for EMCM PPP

Same Infiniband cable as for hybrid 5

EMCM



See Christian Koffmane's & Laci Andricek's talk



- 1 Switcher (only 16 of 32 channels)
- 1 small PXD6
- 1 DCD (only 128 of 256 channels)
- 1 DHP (only 128 of 256 channels)

Kapton (Power & Data)

DHH / DHH Emulator

Possibilities to solder:

6 Switchers (check outputs by external PCB

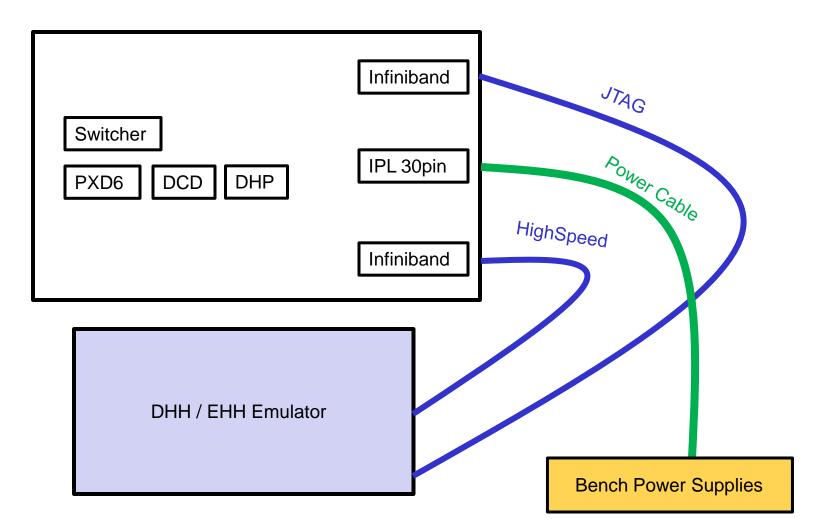
(wirebonds)

- 4 DCDs
- 4 DHPs

Operation similar to hybrid 5



See Florian Lütticke's talk





There are two large PXD matrices working (75µm x 50µm & 100µm x 50µm (CC)) (I06 & I00)

=> For the DESY testbeam (2014) 2 PCBs are required (mirrored)

- 4 Infiniband cables (High Speed DHPs, JTAG DHPs, Switcher Control, Switcher JTAG)
- Power connector
- Cooling (DCDs & DHPs and Switchers)

Plan:

DHP controls Switcher (StrG, StrC, Clk, SerIn, SerOut)

External FPGA provides JTAG for Switcher (TDI, TDO, TMS, TCK, TRST)

Problem:

• DHP does not support GatedMode operation but DHPT does – finished soon enough (Sep 13)?



Is this a serious problem?

JTAG

JTAG for switchers is required for boundary scan and configuring termination resistors ...

=> JTAG will be provided by the **DHH** (in consultation with Igor Konorov)

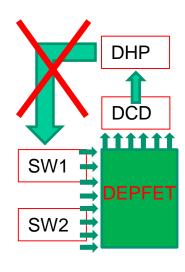
Therefore, an additional Infiniband Connector is required

Switcher Control

DHP does not support GatedMode operation for Switchers

DHPT supports GatedMode Operation => will it be ready (Sep13)?

Control Switcher by **DHH** => Can switch into GatedMode





Switcher Control

Switcher control lines (controlled by DHP or by DHH => discussion was already in the DEPFET-LAB Evo Meeting (March 1))

Both? (either DHP or DHH (online switching)) => Multiplexer needed

Power provided by the Polycover channel of the LMU Power Supply (also included in PowerCable)

Switcher signals:

SERIN SEROUT STRG

STRC

CLK

Need not be provided externally But for GatedMode operation JTAG:

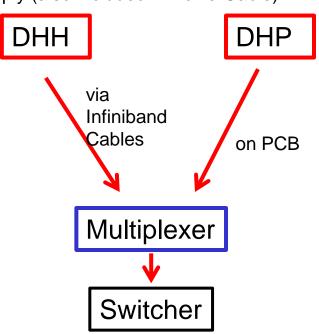
TDI

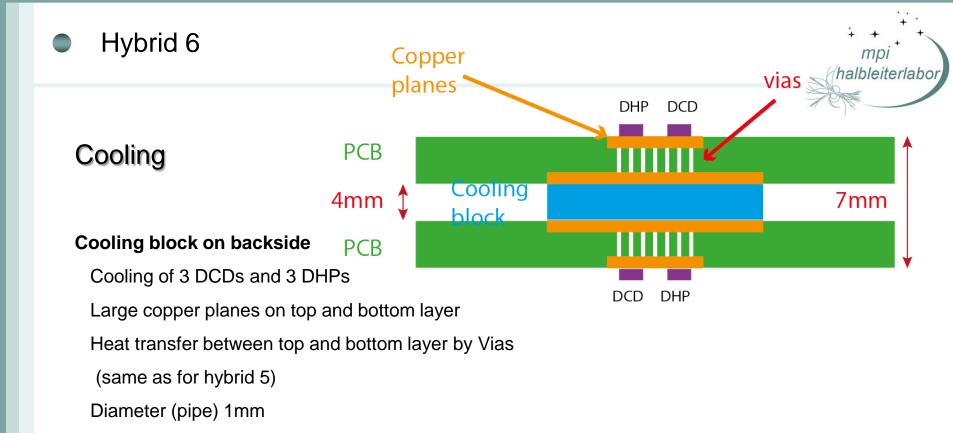
TDO

TCK TMS

TRST

Must be provided externally





Either fluid or CO2

Thickness 4mm (PCB: 1.5mm => distance between PXD detectors: 7mm)

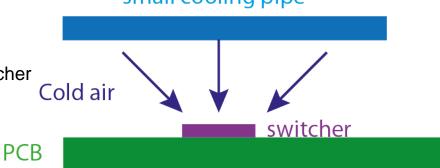
small cooling pipe

Additional Switcher cooling

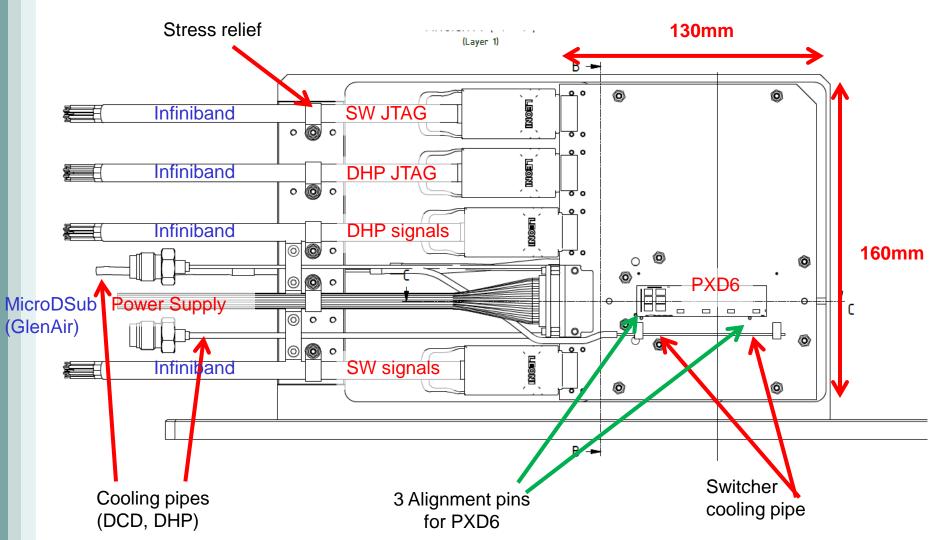
small pipe with ,holes' installed above the switcher

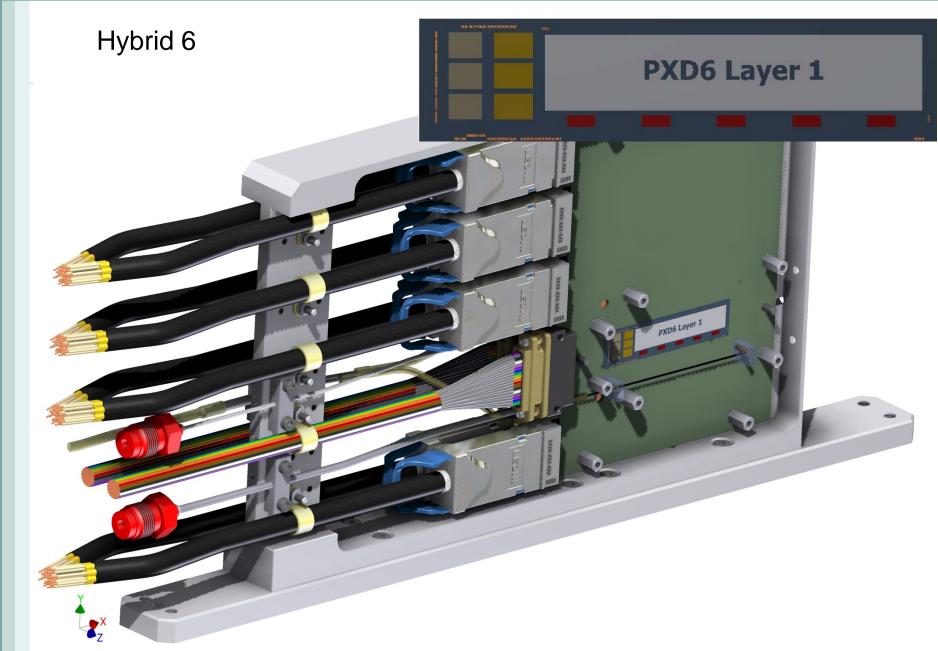
air flow

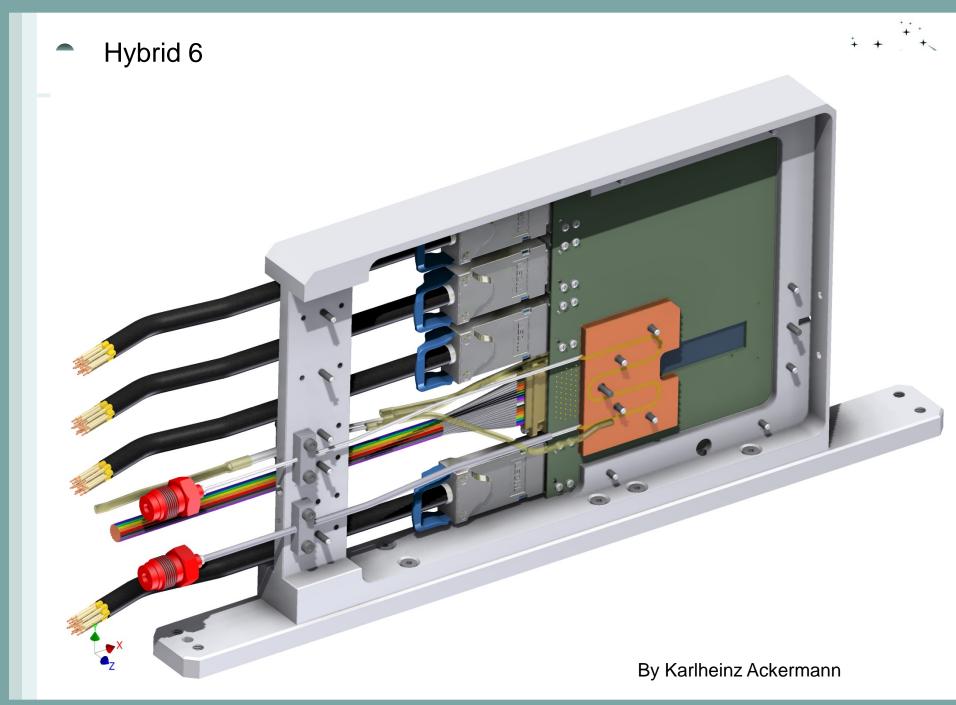
easily removable

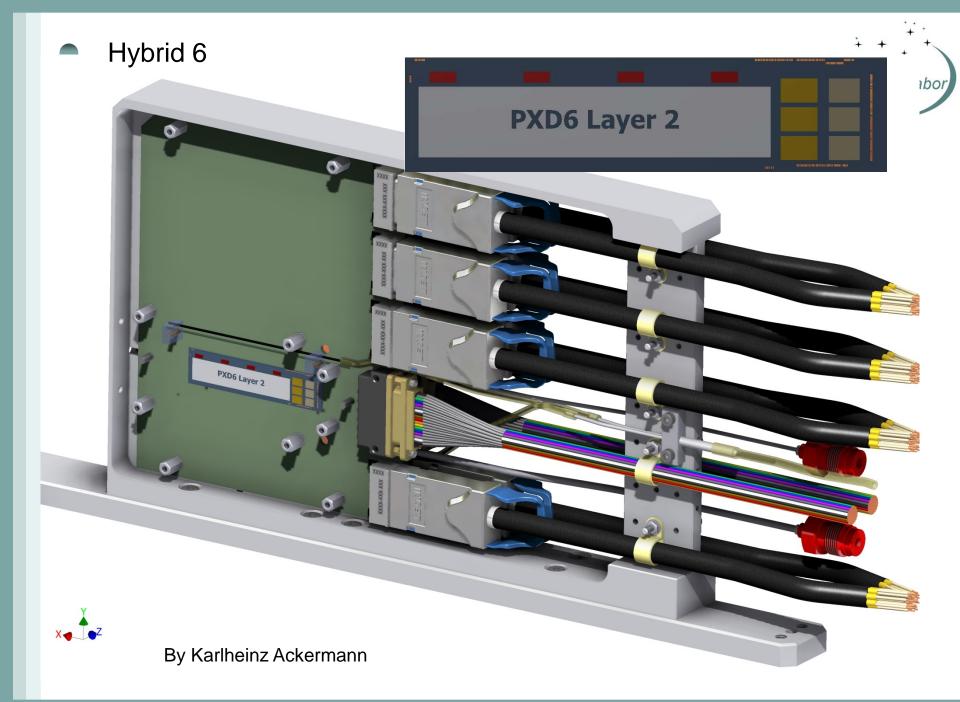












Hybrid 6, design in progress

DHH <=> Switcher JTAG

- 6 to 8 layers
- Place bottom traces to inner layer(s)
- Back drilling (more complex)

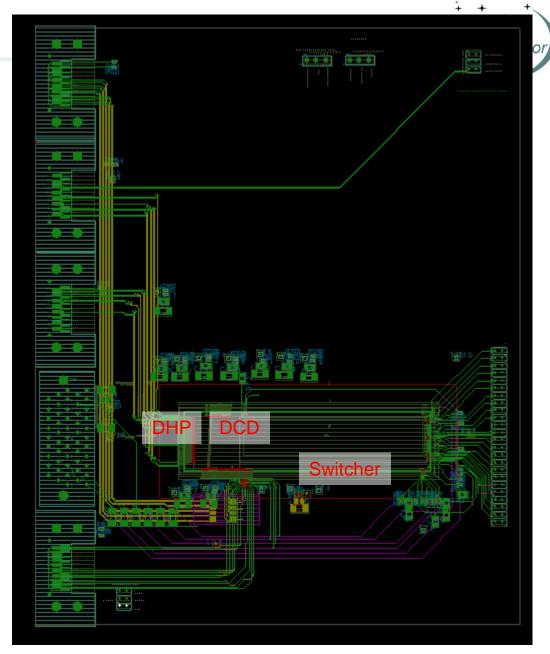
DHH <=> DHP JTAG

DHH <=> DHP control lines



Power Connector

DHH <=> Switcher control lines



Conclusions and Outlook



- 2 long working PXD6 matrices waiting copper deposition
- Testing strategy planned
- PCB design of hybrid 6 in progress
- Open questions: Switcher control Multiplexer in the case that DHPT is not ready
 - => Must be tested on a extra board (needs a few weeks)



Thank you!

Pretests of large PXD6 matrices



- Keep all transistors OFF select only ONE gate (192x4 pixels) and measure I_d vs. V_{gs}
- Measure the characteristics of individual transistors along the ladder
- Check pedestal spread
- Check threshold voltage spread
- Check g_q spread

Hybrid 6 – JTAG (single ended & differential signals)

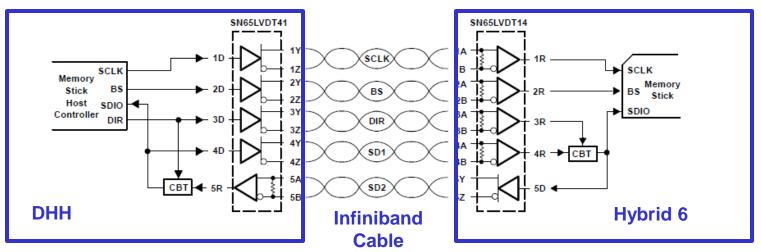


JTAG is provided by the DHH

- => differential signals are favorized + converter (differential -> single ended)
- => SN65LVDT14 (in consultation with Igor Konorov)

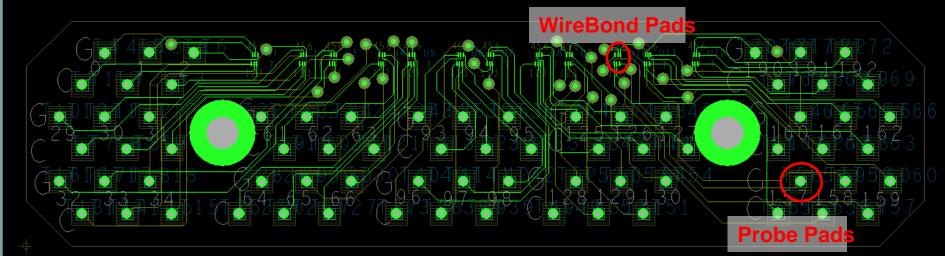
VDD (3.3V) provided by LMU power supply (Polycover channel) (in consultation with Stefan Rummel)

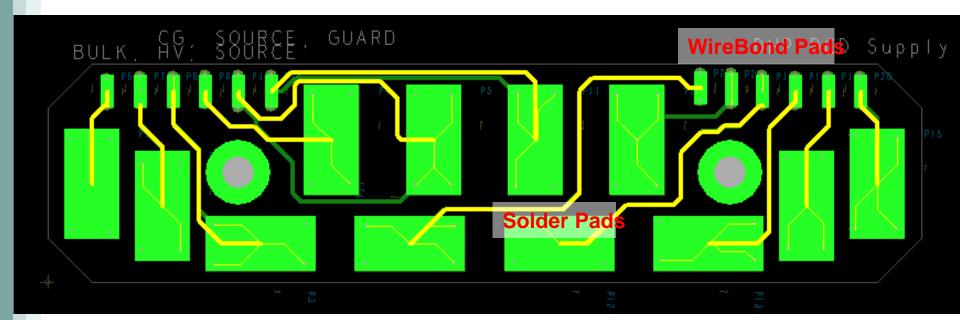
TYPICAL MEMORY STICK INTERFACE EXTENSION



Backup, EMCM







Backup, EMCM



